

**ECE 733**  
**Final, Spring 2006**

This test is open book, open notes. Computers are NOT allowed (calculators are). You have 75 minutes. Turn in answers on your own paper.

**Question 1**

Consider the following cross-section for an interconnect circuit:

- Differential pair.
- Line width = 10  $\mu\text{m}$
- Line thickness = 2  $\mu\text{m}$
- Line Separation = 20  $\mu\text{m}$
- Line material: Aluminum ( $\rho = 4.3\text{E-}8 \Omega\cdot\text{m}$ )
- Dielectric material : BCB.  $\epsilon_r=2.7$ ;  $\tan \delta = 0.0008$
- $\mu = 4\pi\text{E-}7$  (Magnetic permeability)
- $Z_0= 50 \text{ Ohm}$

(a) At what frequency is the skin-depth half of the conductor thickness? [2 points]

$$f_s = \frac{\rho}{\pi\mu(t/2)^2} = 10.9\text{GHz}$$

(b) At what frequency does the attenuation due to the loss tangent exceed the attenuation due to the skin effect? [3 points]

$$\alpha_D = \frac{\pi f \sqrt{\epsilon_R} \tan \delta_D}{c} = 1.37\text{E-}11 * f \quad \alpha_s = \frac{R_{DC}}{2Z_0} \sqrt{\frac{f}{f_s}} = \frac{2150}{100} \sqrt{1/10.9\text{E}9} \sqrt{f} = 2.06\text{E-}4 \sqrt{f}$$

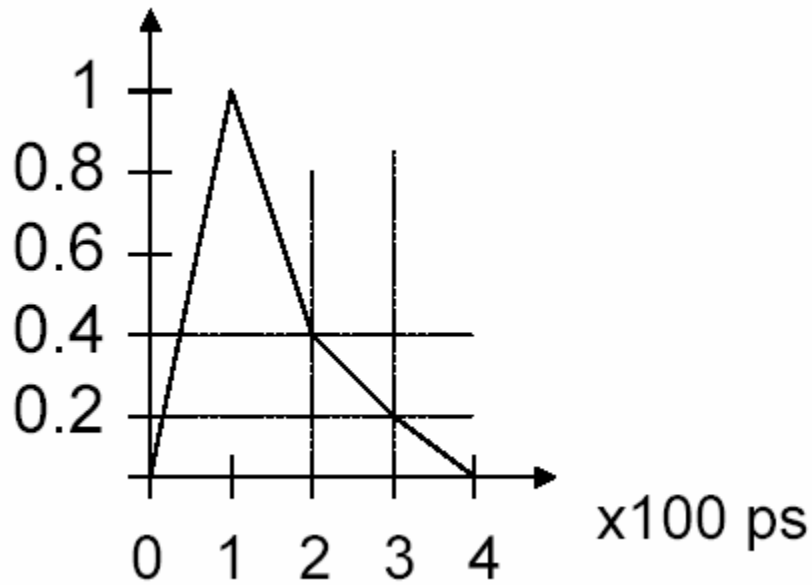
225 THz! (2.25E14 Hz)

(c) Would you get the best Bit Error Rate by using PAM-2 or PAM-4 as your signaling scheme on this line? Carefully explain your answer. [2 points]

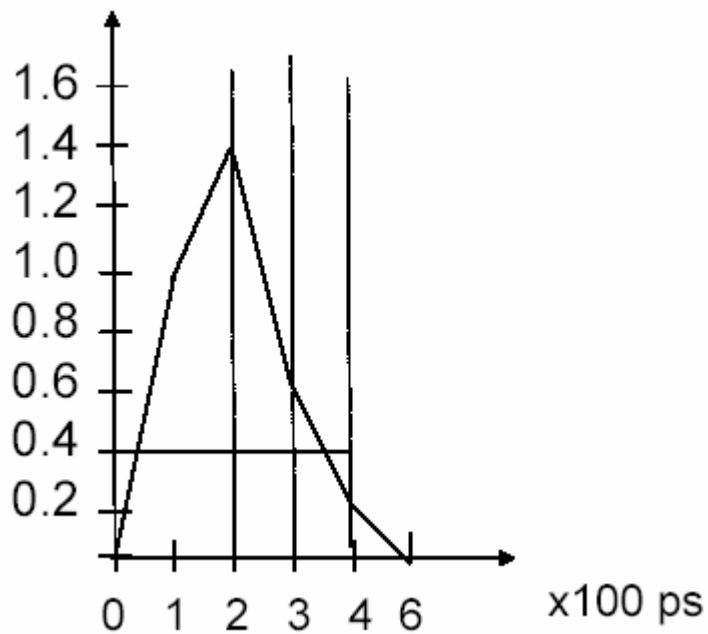
PAM-2, as the frequency roll-off of loss is small.

**Question 2**

Consider an interconnect circuit with the following pulse response to a 010 input operating at 10 Gbps.



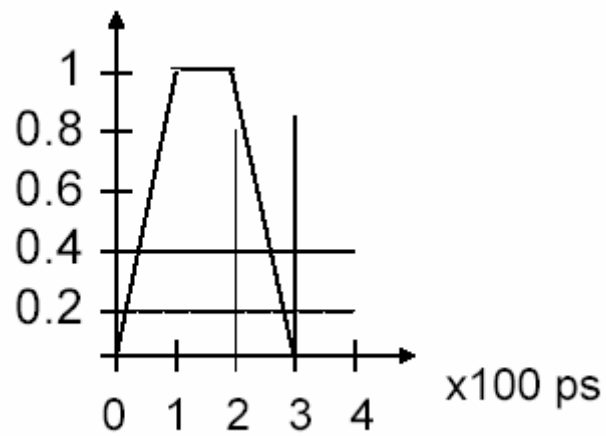
- (a) Based on this waveform, predict the waveform for a 0110 signal operating at 10 Gbps, as it would appear at the end of the same line. [4 points]



- (b) How many taps (i.e. how many flip-flop delays) would you use in a pre-emphasis filter, and what are appropriate tap weights. [3 points]

2, 0.4, 0.2

- (c) Draw the waveform at the end of the line for a 0110 signal operating at 10 Gbps, as produced by the driver with the filter. [2 points]



**Question 3**

Consider the 8T cell, considered in the distributed paper, and described below:

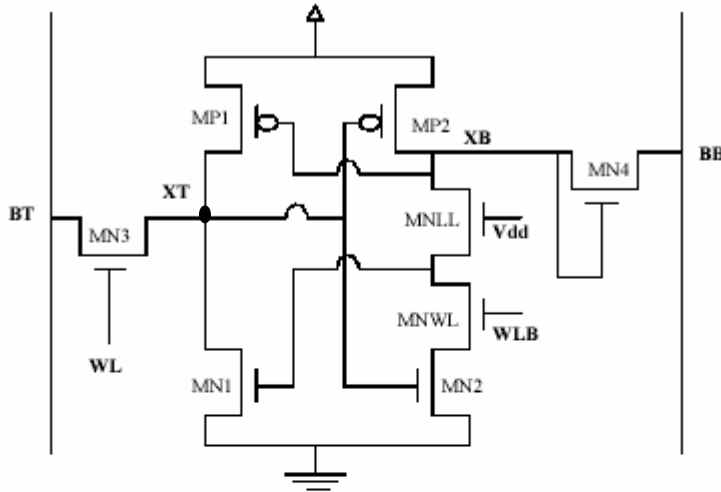


Figure 2. 8T SRAM Cell

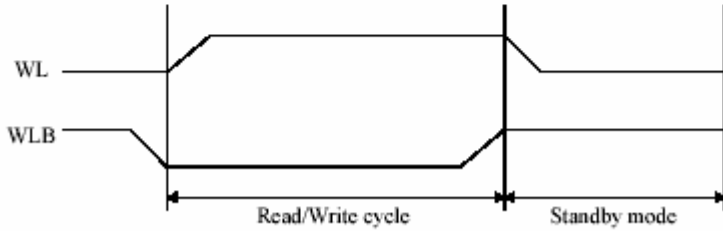


Figure 3. Timing Diagram

Please answer the following questions:

- (a) What are the constraints, if any, on the relative sizes of MN1 and MN3 to read a “0” stored at XT without upsetting the state of the memory? Clearly justify your answer. [2 points]

No constraint, as MNWL=off prevents a logic change.

- (b) For the SRAM to work correctly, it needs to ensure that when reading a stored “1”, then  $(BT, BB) = (1, 0)$  must be met, and for reading a stored “0”, that  $(BT, BB) = (0, 1)$  must be met. What potential issues do you see driving  $BB \rightarrow 0$  if XB is low? Thus, how should the column “load” circuits be redesigned to ensure correct operation? [2 points]

This question was changed in the exam – ignore. A range of answers were accepted.